

Semiconductor parameter analyser - Wafer Probe Station

Semiconductor parameter analyser Agilent 4156C, Agilent 41501B & Wafer Probe Station Karl Suss PSM 6



Contact information

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Technological Offers type

Technological scientific services

Research and innovation areas

- Digital Technologies, Artificial Intelligence, Cybersecurity, 5G, Robotics
- Industry, Materials and Circular Economy
- Science For Engineering and Architecture

ODS



Available from: 2015

Where?

ISOM Semiconductor Devices Group University Optoelectronics and Microtechnology Systems Institute

Keywords: | DC | Electrical characterization

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Description of the services offered

Parameter measurement, current-voltage curves and (static)-voltage capacity. 0 V \pm 200 V, \pm 1 pA \pm 1 A. 4-position Wafer Probe Station.

Needs requested and applications

Sector or area of application

Electronics, optoelectronics, quantum communications

Differential skills

Previous references for provision of services

Equipment description

ISOM. HTSE Telecommunications

Request for service

Protocolo de Acceso
